Notice of References Cited Application/Control No. 10/042,092 Examiner KAMAL B. DIVECHA Applicant(s)/Patent Under Reexamination SCHEER ET AL. Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-6,829,216	12-2004	Nakata, Tsuneo	370/228
*	В	US-2002/0188700	12-2002	Steitle et al.	709/220
*	С	US-6,012,088	01-2000	Li et al.	709/219
*	D	US-6,205,477	03-2001	Johnson et al.	709/220
*	Ε	US-2002/0184484	12-2002	Abboud et al.	713/100
*	F	US-6,735,548	05-2004	Huang et al.	702/179
*	G	US-6,751,658	06-2004	Haun et al.	709/222
*	Н	US-5,835,726	11-1998	Shwed et al.	709/229
*	1	US-6,636,958	10-2003	Abboud et al.	711/173
*	J	US-6,567,849	05-2003	Ludovici et al.	709/223
*	к	US-6,066,182	05-2000	Wilde et al.	717/175
*	L	US-5,978,911	11-1999	Knox et al.	713/1
*	М	US-6,301,612	10-2001	Selitrennikoff et al.	709/220

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Q					
	R					
	s					
	Т					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)				
	υ					
	>					
	w					
	x					

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.